

REMARKS

Claims 1-9 currently remain in the application. Claims 10 and 11 are canceled, and no claims are herein amended.

In said Notice of Allowance and Fee(s) Due dated July 16, 2007, the Examiner stated, in Paragraph 2 in page 2 of the Official Letter, that Japanese Patent Publication Tokkai 61-150080, submitted in an earlier filed information disclosure statement, has not been considered because no translation into English was provided for the office action dated January 7, 2004 for the corresponding Japan Patent Application 2001-323906 and hence that the Examiner could not evaluate the relevance of this reference to the underlying invention. The present RCE is being filed, therefore, with a translation of relevant portions of said Office Action such that the Examiner would be able to determine whether or not this reference is relevant to the patentability of the instant application. A translation into English of this reference (Japanese Patent Publication Tokkai 61-150080) has already been submitted.

The portions of said Office Action considered relevant are translated into English as follows:

The Reference (Japanese Patent Publication Tokkai 61-150080) describes calculating the direction of the edge pixel of the gradation image which is the target for detection of defects by making use of the density gradient and detecting a defect by obtaining an angular difference between edge pixels, and since it is well known to detect a defect from the angle of an edge point selected by the width of an uneven part to be detected, it would be obvious to a person skilled in the art to detect a defect by calculating the direction of an edge pixel of a gradation image which is the target for detection of defects by using the density gradient and obtaining an angular difference between edge pixels "selected by the width (corresponding to the "arbitrarily set distance" of this application) of the unevenness to be detected".

and

It is commonly done in this field of technology to make use of a filter mask of a freely selected size according to the conditions of detection when an edge is being detected.

and

Differential direction "e" of a pixel on an edge (or a pixel with edge flag on) in the Reference is equivalent to the direction of edge pixel in the present

application. It is also known by persons skilled in the art (as described in Japanese Patent Publication 61-009769) that differential direction "e" on an edge pixel is a value indicating the direction of this edge pixel. Thus, it would be obvious for a person skilled in the art to interpret the "angle" mentioned in the Reference as the differential direction "e" used as the value indicative of the direction of this edge pixel and to obtain the difference in differential directions "e" of neighboring pixels with edge flags and to obtain the degree of deformation from the size of this angle (not to obtain the angle of the line connecting the coordinates of neighboring pixels with edge flags on the edge extraction image and to obtain the degree of deformation by the size of the angle. Thus, it would be obvious to a person skilled in the art to calculate the direction of an edge pixel of a gradation image which is the object for detection of defect by using a differential direction and to detect a defect by obtaining the angular difference between edge pixels selected according to the width (corresponding to the freely selected distance of this application) of the uneven part to be detected.

Applicant believes that the claims section in the instant application in the United States has been sufficiently modified and the claim scopes have been significantly changed from the time when the application was originally submitted and hence that the Examiner will find the reasoning presented in this Office Action is largely no longer applicable. In other words, applicant believes that the Examiner will continue to find the present application in condition for allowance even after all the documents submitted in the form of information disclosure statement are considered. Such an action at an early date is earnestly solicited.

Respectfully submitted,



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